Component Title:

TRANSISTORS, MICROWAVE, SMALL SIGNAL, BIPOLAR, BASED ON TYPE BFY 640, 640B, 650B, 740B

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			E	Executive Member: DLR						D	Date: 23/10/2018 32				
Componer	nts (includi	ng series ar	nd fam	nilies) s	ubmitted fo	or Ext	ension	of Qua	alification	Approval:					1
COMPO	ESCC COMPONENT VARIANTS NO.				RANGE OF COMPONENTS					BASED ON		TEST VEHICLE / S	COMPON SIMILA		
5611/009		01 to 03								BFY 640					
5611/010		01 to 04								BFY 64	0B, 6	650B	50B BFY640-04(ES)		
5611/011 01			BFY 740B					BFY 74	0B		2. (0.00 0.000)				
Component Manufacturer 2				Location	of Ma	anufact	turing F	Plant(s)		3		4			
Infineon Technologies AG				Am Campeon 1-12 D- 85579 Neubiberg Germany				Date:	Date of original qualification approval: Date: 01/09/2012 Certificate Ref No. 322						
				5							6				7
	ce of qual	ification test			used:			-		Specificati		refere	fication Extension Report ence and date:	rt	
Generic:	5010	Issue	: 0:	2	No [Yes	9	(supply	details in B	OX		LR10, Iss 1, April 2018 LR11, Iss 1, April 2018		
Detail(s):	5611/00	9 Issue	: 0:	2	Deviatio	n fron	n curre	nt Spe	cifications	s:					
	5613/00	4 Issue	: 0	2	No 0	3	Yes	V	(Supply	details)					
															8
Summary	of procure	ment or equ	uivaler	nt test r	esults duri	ng cu	rrent va	alidity p	period in s	support of t	his a	pplication	on (those to ESCC listed	first)	
	ct Name	100	sting l	5 25				Date code	de Quantity Delivered						
					-										
					1							Ì			
					_										
PID chang	es since l	ast MoQ			9 Current PID			Verified			B. Gökgöz		10		
None								by:				N	lame of Executive Repre	sentative	L
Hone	_							Ref	No:	Generic P	ID:		A63500-GEPID-P000,		018
Minor*	\boxtimes									Detail PID	:		BFY640: A63500-T580	-P000, Issue 3a, 1	18.10.2018
Major*		*Provide d	otaile	in hov:	Issue: See above				е	Rest: A63500-T1580B-P000, Issue 3a, 18.10.2018 Date: See above					
Major	_	Please se			3			1000000	Date:	26/10/201					
					352										11
Current Manufacturing facilities surveyed by:						1	r. Kaupis	ch		or	17-	-18/10/2018			
					(Nam	e of Ex	cecutive F	Representa	tive)			(Date)			
Satisfactor	rv:	Yes	×		No		Ex	plain							
54115140101	,.	, 03	KN		110	_	-^	E							
Report Re	ference:	_IFX-A	AUD-2	018			<u> </u>								

	APPLICATI	ON APPROVAL	Page 2						
ESCC	Component title:	TRAN ON T	NSISTOI YPE BF	RS, MIC Y 640,	CROWAVE, SMA 640B, 650B, 740B	LL SIGNA B	L, BIPOLAR, BASED	Appl. I	No.
	Executive Member:	DL	R			Date:	23/10/2018	3220	
Failure Analysis, DPA, NCCS available:	Yes		No		(Supply data)			ŀ	12
Ref. No's and purposes:									
The undersigned hereby certifies on behalf that the appropriate documentation has bee (except as stated in box 15;) - that the repo DLR as the responsible Executive Member	en evaluated; - that ful rts and data are availa	comp	liance to the ESC	all ES	CC requirements cutive and therefo	is evidend re applies	on behalf of		13
							Billack gål	93	
Date: 23/10/2018						(Si	B. Gökgöz gnature of the Executive 0	Coordinator)	
Continuation of Boxes above:		-							14

Component title:

TRANSISTORS, MICROWAVE, SMALL SIGNAL, BIPOLAR, BASED ON TYPE BFY 640, 640B, 650B, 740B

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Non comp	pliance to ESCC_requirements:			15
No.:	Specification	Paragraph	Non compliance	L
1	ESCC 5010	CHART F4	No periodic repetition of Endurance Subgroup	
2	ESCC 5010 issue3 (APRIL 2017)		ISSZ USED FOR MAINTENANCE OF QUALIFICATION	
Additional noncompl		ESCC qualification or rationale for acceptability	of	16
		ology for maintenance of qualification regarding	similarity in § 7	
Revi	SED PID APPROVED	IN OCT. 2018		
Executive	e Manager Disposition			17
	on Approval: Yes 🗹 No 🗆			
Action / R	ACHIGINS.		ZU DI BRITTASCHA	DE)
			Signature of ESA Head of Product Assurar Safety Department	nce and

TRANSISTORS, MICROWAVE, SMALL SIGNAL, BIPOLAR, BASED ON TYPE BFY 640, 640B, 650B, 740B Component Title:

Executive Member: Date: 23/10/2018 Page 4

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ANNEX 1: LIST OF TESTS DONE TO SUPPORT EXTENSION OF QUALIFICATION

Tests conducted in compliance with:

ESCC 5010 generic specification; Chart V (for ESCC/QPL parts);

Tests vehicle identification/description:

1814LR10	BFY640-04(ES), EnvMechSG, AssCapSG, DecapSG, 1709A	
1814LR11	CFY67-08(ES), AssCapSG, 1632A	

Detail Specification reference: 5613/004 and 5611/009

Chart F4A	Test	Tick when done	Conditions	Date Code Diffusion Lot	Tested Qty	No. of Rejects	Comments if not performed. Comments on Rejection
	Thermal Shock Test	×	MIL-STD-202 Test Method 107 Test Condition B, 100 cycle	1709A	10	0	acc. Detail Spec
roups	Shock Test		MIL-STD-750 Test Method 2016				n.a. acc. Detail Spec
Environmental/Mechanical Subgroups	Vibration Test		MIL-STD-750 Test Method 2056				n.a. acc. Detail Spec
	Constant Acceleration		MIL-STD-750 Test Method 2006				n.a. acc. Detail Spec
	Seal Test (Fine and Gross Leak)	×	MIL-STD-750 Test Method 1071	1709A	10	0	
	Moisture Resistance	\boxtimes	MIL-STD-750 Test Method 1021	1709A	10	0	
	Electrical Measurements at Room Temp.	×	Table 2 of the Detail Specification	1709A	10	0	
	External Visual Inspection	×	ESCC Basic Specification No. 20500	1709A	10	0	
Endurance Subgroup*	Operating Life		MIL-STD-750 Test Method 1026				Former data from Wafer available
	Electrical Measurements during Endur. Test		Table 6 of the Detail Specification				Former data from Wafer available
	External Visual Inspection		ESCC Basic Specification No. 20500				Former data from Wafer available

^{*} LAT2 on actual wafer was performed satisfactorily on Assembly Lot 1041.1, Date Code: 1043A



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Component title:

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Chart V	Test	Tick when done	Conditions	Date Code Diffusion Lot	Tested Qty	No. of Rejects	Comments if not performed. Comments on Rejection
ability	Solderability Test		MIL-STD-750 Test Method 2026	1632A	2 4	0 0	
Assembly Capability Tests	Permanence of Marking	×	ESCC Basic Specification No. 24800	1632A	2 4	0	
Assen	Terminal Strength		MIL-STD-750 Test Method 2036	1632A	2 4	0	
ation	Internal visual inspection	×	ESCC Basic Specification No. 20400	1632A 1709A	2 6	0	
De- encapsulation Tests	Bond Strength	×	MIL-STD-750 Test Method 2037	1632A 1709A	2 6	0	
euc	Die Shear	⊠	MIL-STD-750 Test Method 2017	1632A 1709A	2 6	0	



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NOTES ON THE COMPLETION OF THE APPLICATION FORM FOR ESCC QUALIFICATION EXTENSION APPROVAL

ENTRIES Form heading	shall indicate: - the title of the component as given in its detail specification or the name of the series, family; - the Executive Member; - the entering date; - the certificate number and its sequential suffix.
Box 1	shall provide details given in the table; in particular there shall be listed: - the variants or range of variants; - the range of components (the ESCC code is recommended to indicate the values or values range, the tolerance, the voltage, etc); the designation given in the detail specification as 'base on'; - under Test Vehicle enter either an ESCC code or the specific characteristic capable of identifying the component tested (e.g., voltage of coil for a relay); - under component similar enter a cross if relevant.
Box 2; 3 and 4	As per QPL entry; otherwise, an explanation of the changes must be supplied.
Box 5	Will show the ESCC Generic and Detail specifications, including issue number and revision letter, current at the time the tests reported were performed. If the specifications are different from those current on the date of the application, see Box 6.
Box 6	Will show the deviations from the Generic and Detail Specifications listed in Box 5, in particular deviations from testing. In case of deviations this must be listed in Box 15. In case the referenced specification in Box 5 have currently a different issue and/or revision indicate also whether the test data deviates or not from such current documents.
Box 7	Must reference the report(s) supplied in support of the application.
Box 8	Should provide the details of procurement to the full ESCC System, documentation of all of which should already have been delivered to the ESCC Executive under the terms of the relevant Generic Specification. An appropriate table has been drawn in this box.
Box 9	If the PID evolved after the Original Qualification or after the last Extension of Qualification, adequate details of such evolution shall be provided together with the reasons for the changes. Major changes shall be clearly marked.
Box 10	Identify the current PID issue status, date and actual date of verification. The date of verification of the current PID should be arranged as close as possible to the required date of extension.
Box 11	This box can be completed only after a physical visit to the plant to confirm that no unexplained changes occurred and that the practices, procedures, material, etc. used in manufacturing the components are as described in the PID. This survey shall be carried out in accordance with the requirements of ESCC Basic Specification No. 20200 and its findings shall be recorded.
Box 12	Provide details of, or reference to, any Destructive Physical Analysis (DPA) and Failure Analysis reports as well as any Nonconformance(s) (NCCS) occurred during the qualification validity period, stating if established corrective action have produced satisfactory results.
Box 13	Enter only the name of the Executive Member (i.e., CNES, DLR, ESTEC, etc.) and the signature of the responsible Executive Coordinator.
Box 14	To be used when there is a need to expand any of the boxes from 1 through 12. Identify box affected and reference the Box 14 in the relevant Box. Box 14 can be broken into 14a, 14b, etc. if several boxes have to be expanded.
Box 15	Fill in Table as requested.
Box 16	Any additional action deemed necessary by the Executive Member to bring the submitted data to a standard likely to be accepted by the ESCC Executive should be listed herein or the reason(s) to accept the noncompliance.
Box 17	All Executive Manager recommendations on the application itself, special conditions or restrictions, modifications of the QPL or QML entry, letters to the manufacturer, etc. shall be entered clearly in Box 19, signed by the representative for ESA, and dated.
Box 18	Fill in Table as requested.
Box 19	Confidential Details of PID changes including those of a confidential nature, shall be provided.
Box 20	State noncompliance with reference to specification(s) and paragraph(s). To simplify reference in Box 16 each nonconformance shall be sequentially numbered. If relevant state 'None'.
Box 21	Any additional action deemed necessary by the Executive Member to bring the submitted data to a standard likely to be accepted by the ESCC Executive should be listed herein or the reason(s) to accept the noncompliance.
Box 22	Additional Comments.